

MCTR 702_1

Master Advanced Mechatronics

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Mechatronics common framework **Lecture 1**

2021







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Lecture 1

RELIABILTIY

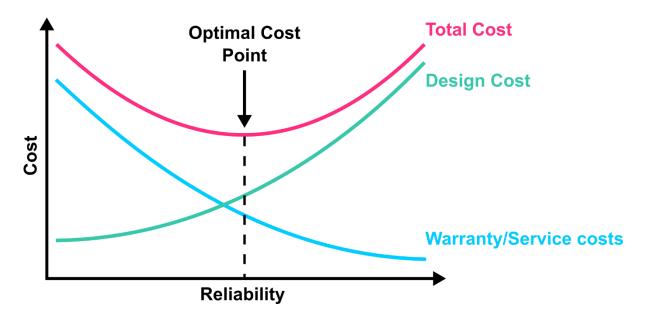
- Introduction to Dependability
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- 2. Predictive Reliability
- 3. Reliability Modelling







Costs vs Reliability



- Effects of Over-reliability in Development
 - Product is too expensive for target market
 - Product is later getting to market
 - Company is behind technology leaders due to slow program development cycles

- Effects of Under-reliability in Development
 - High field Return Rate
 - High Warranty Cost
 - Loss of product sales once low reliability is known in market
 - Loss of market share in all product lines due to poor brand perception.





1. RELIABILITY FUNCTIONS & ESTIMATORS







Reliability Functions & Estimators

Reliability functions

- The failure function F(t)
- The reliability function R(t)
- Complementarity between F(t) and R(t)
- The failure rate $\lambda(t)$
- The density function f(t)

Reliability function estimators

- Estimation of F(t)
- Estimation of R (t)
- Estimation of $\lambda(t)$
- Estimation of f (t)
- Estimation of the mean E(t)

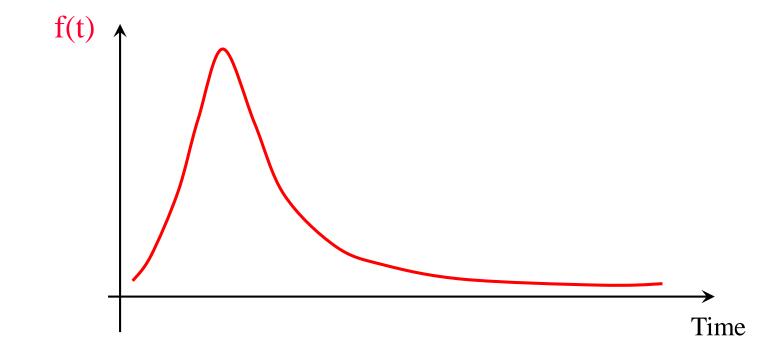






The density function: f(t)

It represents the histogram of the relative failures as a function of time or the probability frequency of the relative failures relative to the unit of time.







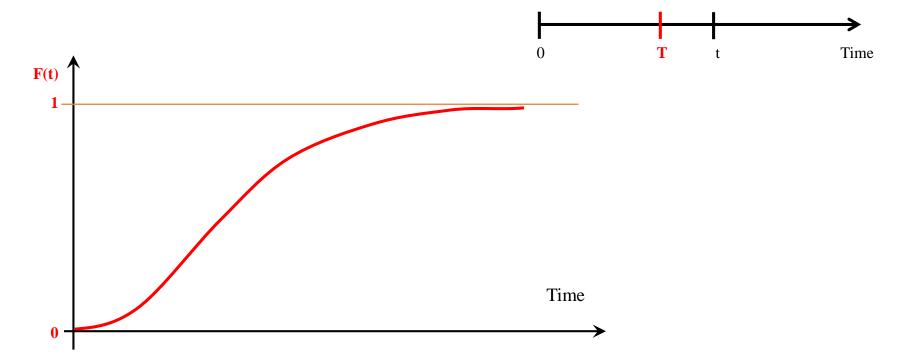


The failure function: F(t)

It is measured by the probability that an entity E fails over the time interval [0, t]: F(t) = Pr(E failing on [0, t])

That is, if we assume that an entity is failing at a date T:

$$F(t) = Pr(T \le t)$$







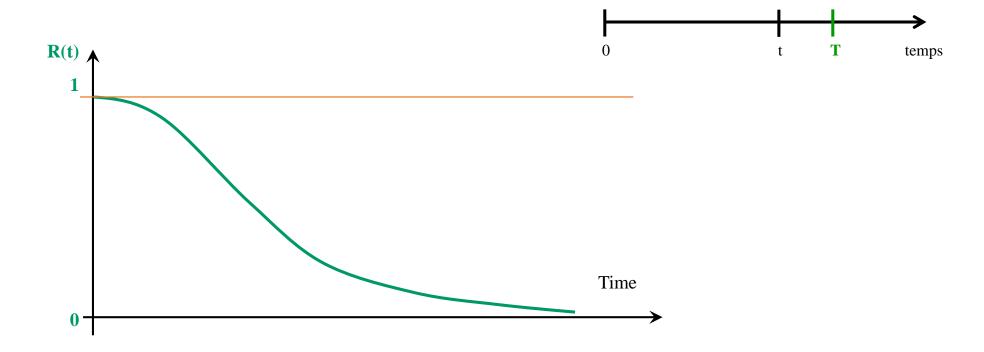


The reliability function: R(t)

It is measured by the probability that an entity E is non-faulty over the time interval [0, t]: R(t) = Pr(E not failing on [0, t])

That is, if we assume that an entity is failing at a date T:

$$R(t) = Pr(T>t)$$





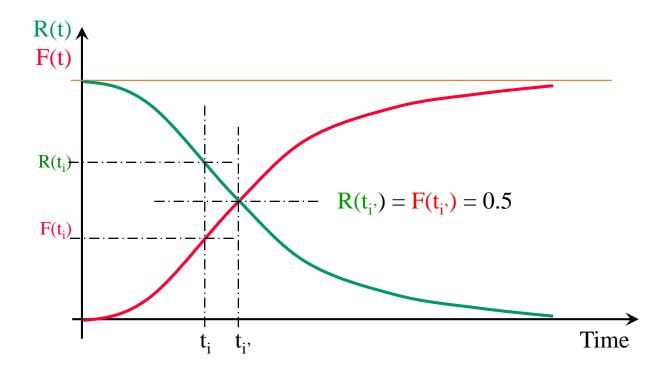




Complementarity between F(t) and R(t)

For a given system, $\forall t = ti$: we have

$$R(ti) + F(ti) = 1$$









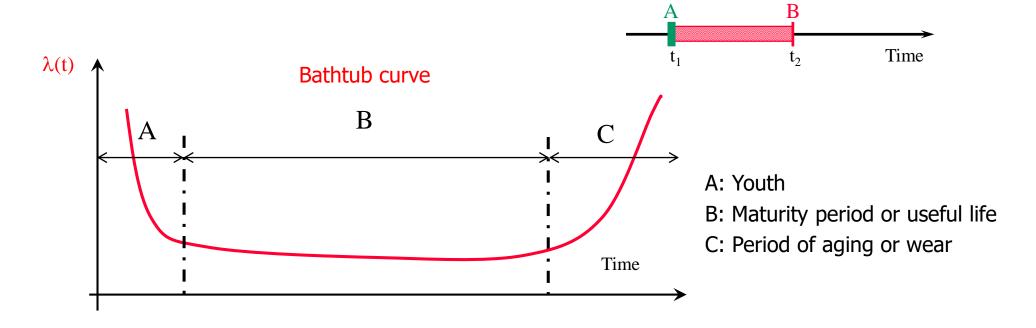
The failure rate: $\lambda(t)$

It expresses the speed of arrival of failures at time t, or the evolution of the conditional probability of failure during the life of the syst. (failure/product and unit of time)

A: Event "product runs at t1"

B: Event "product fails between t1 and t2"

 $\lambda(t) = \Pr(B/A) / (t2 - t1)$











Estimators

It is obviously not realistic to calculate failure rates by building many units and running them for many hours, under expected operating conditions.

This is especially true for well-designed and properly built supplies, with extremely low failure rates, where the number of supplies and hours required to get valid results would be in the thousands.

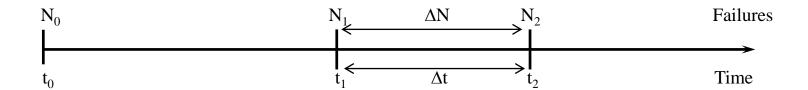
Instead based on representative samples of a population statistical analysis techniques can be used to estimate failure rates.







Estimation of the reliability functions



N: total number of products put into operation at time t0 (sample size)

N0: number of failures at t0 (generally equal to 0)

N1: number of failures at t1 N2: number of failures at t2

 ΔN : number of failures on the interval [t1, t2]

 Δt : time interval [t1, t2]

Reliability function estimators depend on the value of N (number of products put into operation)

N	1 <n≤20< th=""><th>20<n th="" ≤50<=""><th>N>50</th></n></th></n≤20<>	20 <n th="" ≤50<=""><th>N>50</th></n>	N>50
Estimator	Median Ranks	Average Ranks	Cumulative Frequencies







Failure estimators: F(t)

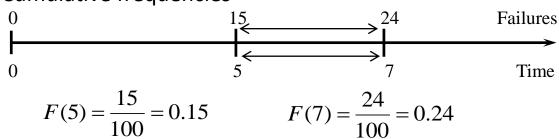
Point estimator at time t

$$F(t) = \frac{N_t - 0.3}{N + 0.4}$$

$$F(t) = \frac{N_t}{N+1}$$

$$F(t) = \frac{N_t}{N}$$

Example (N = 100) \rightarrow Cumulative frequencies





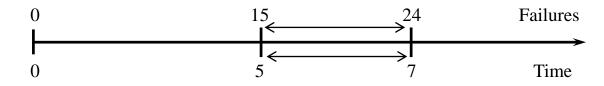


Reliability estimators: R(t)

Point estimator at time t

Whatever the value of N, first compute the estimator of F and then apply the complementarity relation R(t) = 1 - F(t)

Example (N = 100)



$$R(5) = 1 - 0.15 = 0.85$$

$$R(5) = \frac{100 - 15}{100} = 0.85$$

$$R(7) = 1 - 0.24 = 0.76$$

$$R(7) = \frac{100 - 24}{100} = 0.76$$







Density estimators: f(t)

Interval estimator (failure/product and unit of time)

Median ranks if 1<N≤20

$$f_{[t1;t2[} = \frac{\Delta N}{(N+0.4) \times \Delta t}$$

Average ranks if 20<N≤50

$$f_{[t1;t2[} = \frac{\Delta N}{(N+1) \times \Delta t}$$

Cumulative frequencies if N>50

$$f_{[t1;t2[} = \frac{\Delta N}{N \times \Delta t}$$

Example (N = 100) 0 15 9 24 Failures 5 2 7 Time $f_{[5;7[} = \frac{9}{100 \times 2} = 0.045 failures/product & t.u.$







Failure rate estimators: $\lambda(t)$

Estimator on interval (failure/product and unit of time) (f/R)

Median ranks if 1<N≤20

$$\lambda_{[t1;t2[} = \frac{\Delta N}{(N+0.7-N_1)\times \Delta t}$$

Average ranks if 20<N≤50

$$\lambda_{[t1;t2[} = \frac{\Delta N}{(N+1-N_1)\times \Delta t}$$

Cumulative frequencies if N>50

$$\lambda_{[t1;t2[} = \frac{\Delta N}{(N - N_1) \times \Delta t}$$

$$\lambda_{[5;7[} = \frac{9}{85 \times 2} = 0.053 \text{ failures/product \& t.u.}$$





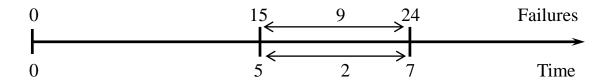


Average estimators: E(t)

Interval Estimator

Whatever the value of N, first calculate the estimator of λ and then apply the inverse relation $E(t) = 1/\lambda(t)$

Example (N = 100)



$$E(t)_{[5;7[} = \frac{1}{0.053} = \frac{85 \times 2}{9} = 18.89 \text{ u.t.}$$















Predictive Reliability

Definition

 Predictive reliability (predicted or theoretical) is calculated on the basis of a mathematical model defined from the functional decomposition of the system into subsets, components, etc. and the estimated or predicted reliability of its components

Analysis and calculation procedure

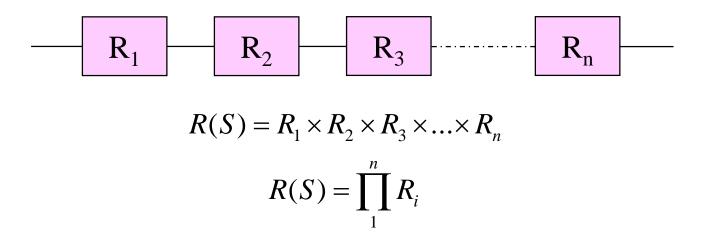
- Decompose the system into components (parts, subsystems ...) and establish the functional links between the components
- Identify component reliability models or collect reliability at a given time
- Search for a model of the system and calculate its reliability







Reliability of the serial system (S)



 R1, R2, R3, ... Rn are the elementary reliabilities of the system components at a given time

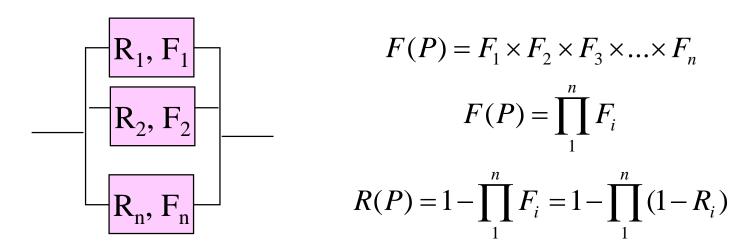






Reliability of the parallel system (P)

1 only component on "n" must operate (system 1/n by default)



 R1, R2,... Rn and F1, F2,... Fn are respectively the elementary reliabilities and failures of the components of the system at a given time

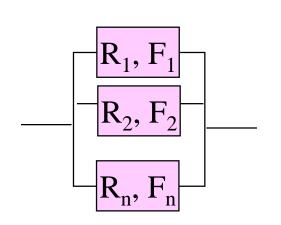






Reliability of the parallel system (k/n)

"k" components on "n" must operate simultaneously (system k/n notation required)



$$B(p,k,n) = C_n^k p^k (1-p)^{n-k}$$
 binomial

$$with: C_n^k = \frac{n!}{k!(n-k)!}$$

$$R(P) = B(p, k, n) + B(p, k+1, n) + B(p, k+2, n) + ... + B(p, n, n)$$

$$R(P) = \sum_{i=k}^{n} C_{n}^{i} p^{i} (1-p)^{n-i}$$

 $n \rightarrow total$ number of components

 $p \rightarrow probability \ of \ success \ (reliability \ of \ a \ component)$

 $k \rightarrow number\ of\ components\ to\ operate\ simultaneously$

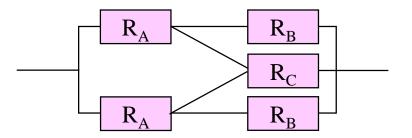
R1, R2, ... Rn and F1, F2, ... Fn are respectively the elementary reliabilities and failures of the components of the system at a given time (binomial law applicable only if the R are identical, otherwise, application of the truth table)



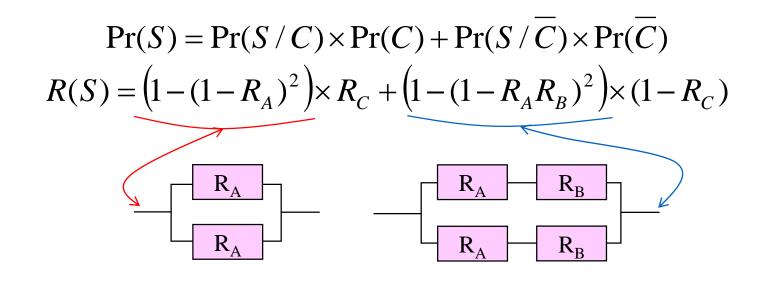




Reliability of a complex system



Baye's theorem









Application to exponential model

R(t) =
$$e^{-\lambda t}$$
 and F(t) = $1-e^{-\lambda t}$ with: $\lambda = 1/E(t)$ (failure rate)

The serial system

The parallel system (2 components)

$$R(t) = e^{(-t\sum_{i=1}^{n} \lambda_i)} = e^{(-t\lambda_S)}$$

$$R(t) = 1 - \prod_{i=1}^{n} (1 - e^{(-\lambda_i t)})$$

$$R(t) = e^{-\lambda_1 t} + e^{-\lambda_2 t} - e^{-(\lambda_1 + \lambda_2)t}$$

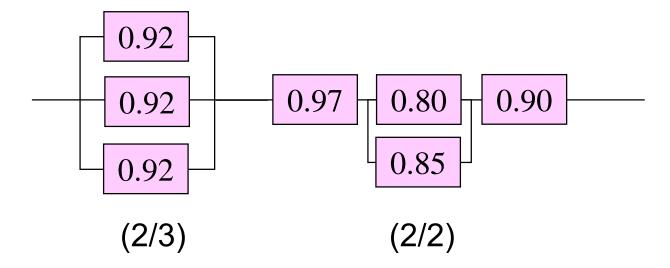






Example

The given values correspond to the reliability of the components at a given time



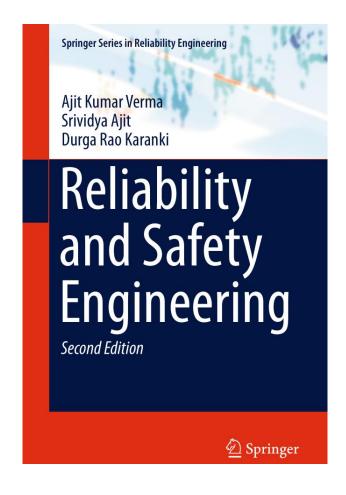
Calculate the predictive reliability of this system

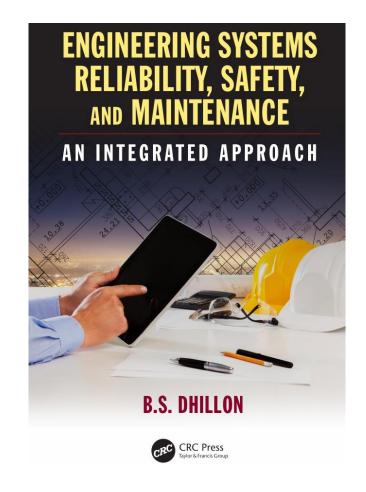






Relevant books











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